

FPD Metrology Japan TC Chapter Liaison Report

For FPD Metrology Korea TC Chapter Meeting

January 22, 2018

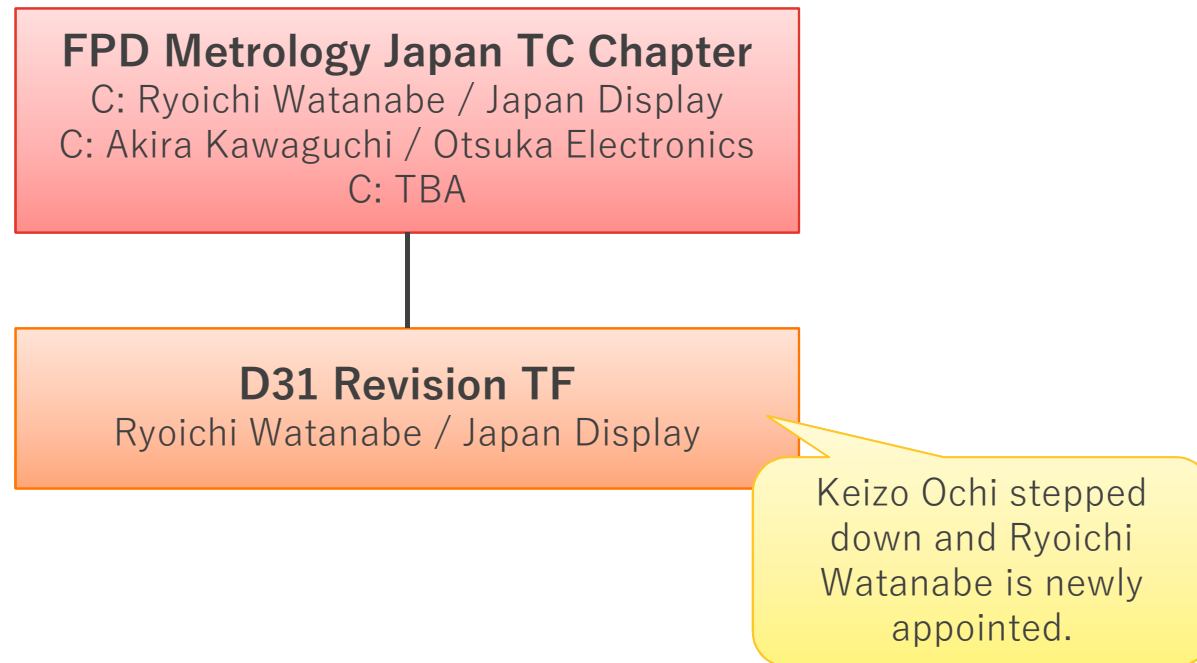
Contents

- Leadership
- Current Committee Structure
- Meeting Information
- Committee Activities
 - Ballot
 - New Activities
 - Five Year Review
 - SNARF Abolished
- Task Force Update

Leadership

- Committee Co-chairs
 - Ryoichi Watanabe/ Japan Display
 - Akira Kawaguchi/ Otsuka Electronics
- Leadership Change
 - Keizo Ochi stepped down from the D31 Revision Task Force leader due to his retirement.
 - Ryoichi Watanabe is newly appointed as the Task Force leader.

Current Committee Structure



Meeting Information

- Last Meeting
 - September 15, during Japan Standards Fall 2017 Meetings at SEMI Japan, Tokyo, Japan
 - * It was a joint meeting of the FPD Materials & Components Japan TC Chapter and the FPD Metrology Japan TC Chapter
- Next Meeting
 - April, 2018 during Japan Standards Spring 2018 Meetings at SEMI Japan, Tokyo, Japan (Date to be decided)
 - * It will be a joint meeting of the FPD Materials & Components Japan TC Chapter and the FPD Metrology Japan TC Chapter

Committee Activities

- Ballot: None
- New Activities: None
- Five Year Review: None
- SNARF Abolished: None

Task Force Updates

- D31 Revision Task Force
 - Doc.6101, Line Item Revision to SEMI D31-0213, with title change from “Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection” to “Guide for Definition of Measurement Index (DSEMU) for Luminance Mura in FPD Image Quality Inspection”
 - Line Item 1: Correct title and concomitant text of SEMI D31
 - Passed as balloted at the TC Chapter meeting on April 7, 2017
 - Passed at A&R in May, 2017
 - Waiting for the proof

Thank you!

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